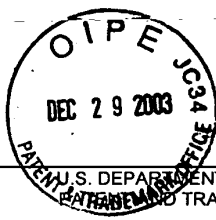


FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-987		SERIAL NO. 09/869,274	
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT A. NISHIMURA et al			
				FILING DATE June 26, 2001		GROUP	
U.S. PATENT DOCUMENTS							
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA	6,030,890	2/29/00	Iwabuchi			
	AB	6,008,543	12/28/99	Iwabuchi			
	AC	5,554,940	9/10/96	Hubacher			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
	AL	4-26537	3/3/92	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AM	4-96343	3/27/92	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AN	5-218042	8/27/93	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AO	8-250498	9/27/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AP	8-64633	3/8/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	AR	IEEE/CPMT INTL ELECTRONICS MANUFACTURING TECHNOLOGY SYMPOSIUM, "Impact of Wafer Probe Damage on Flip Chip Yields and Reliability", M. Varnau et al, pp. 293-297.					
	AS						
	AT						
EXAMINER				DATE CONSIDERED			



FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-987		SERIAL NO. 09/869,274		
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT A. NISHIMURA et al				
				FILING DATE June 26, 2001		GROUP		
U.S. PATENT DOCUMENTS								
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)	
	AA							
	AB							
	AC							
	AD							
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
FOREIGN PATENT DOCUMENTS								
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	8-340029	12/24/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM	8-29451	2/2/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AN						<input type="checkbox"/>	<input type="checkbox"/>
	AO						<input type="checkbox"/>	<input type="checkbox"/>
	AP						<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)								
	AR							
	AS							
	AT							
EXAMINER				DATE CONSIDERED				